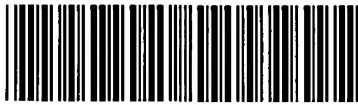


**Search Notes (continued)**



Application/Control No.

10/534,274

Examiner

Pablo N. Tran

Applicant(s)/Patent under  
Reexamination

HIRANO ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
370	328	07/18/07	pl
	503		
	203		
	210		
	208		
	500		
	516		
	509-512		
	520		
	207		
	252		
489	68		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Base / Word	07/18/07	pl